

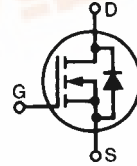
HiPerFET™ Power MOSFETs
ISOPLUS247™
 (Electrically Isolated Backside)

IXFR 34N80

$V_{DSS} = 800 \text{ V}$
 $I_{D25} = 28 \text{ A}$
 $R_{DS(on)} = 0.24 \text{ } \Omega$
 $t_{rr} \leq 250 \text{ ns}$

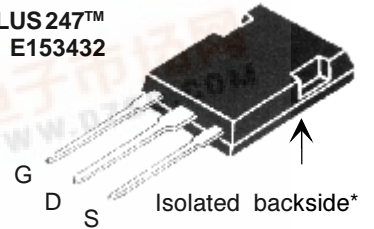
Single MOSFET Die
 Avalanche Rated

Preliminary Data Sheet



Symbol	Test Conditions	Maximum Ratings
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	800 V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	800 V
V_{GS}	Continuous	± 20 V
V_{GSM}	Transient	± 30 V
I_{D25}	$T_C = 25^\circ\text{C}$ (MOSFET chip capability)	28 A
I_{DM}	$T_C = 25^\circ\text{C}$, Note 1	600 A
I_{AR}	$T_C = 25^\circ\text{C}$	150 A
E_{AR}	$T_C = 25^\circ\text{C}$	60 mJ
E_{AS}	$T_C = 25^\circ\text{C}$	3 J
dv/dt	$I_S \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$ $T_J \leq 150^\circ\text{C}$, $R_G = 2 \text{ } \Omega$	5 V/ns
P_D	$T_C = 25^\circ\text{C}$	400 W
T_J		-55 ... +150 $^\circ\text{C}$
T_{JM}		150 $^\circ\text{C}$
T_{stg}		-55 ... +150 $^\circ\text{C}$
T_L	1.6 mm (0.063 in.) from case for 10 s	300 $^\circ\text{C}$
V_{ISOL}	50/60 Hz, RMS t = 1 min	2500 V~
Weight		5 g

ISOPLUS247™
 E153432



G = Gate D = Drain
 S = Source

* Patent pending

Features

- Silicon chip on Direct-Copper-Bond substrate
- High power dissipation
- Isolated mounting surface
- 2500V electrical isolation
- Low drain to tab capacitance (<25pF)
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control

Advantages

- Easy assembly
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 3 \text{ mA}$	150		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8 \text{ mA}$	2.0		4.0 V
I_{GSS}	$V_{GS} = \pm 20 \text{ V}$, $V_{DS} = 0$			$\pm 100 \text{ nA}$
I_{DSS}	$V_{DS} = V_{DSS}$, $V_{GS} = 0 \text{ V}$		$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	100 μA 2 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = I_T$ Notes 2, 3			0.24 Ω

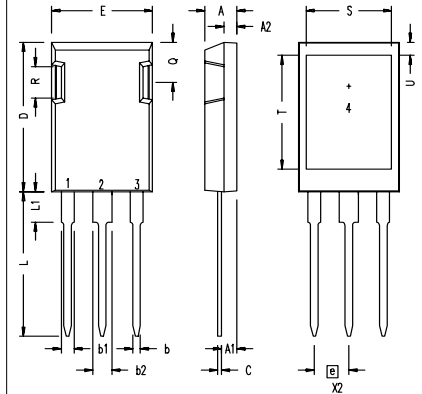


Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
			min.	typ.	max.
g_{fs}	$V_{DS} = 10\text{ V}; I_D = I_T$	Notes 2, 3	20	35	S
C_{iss}	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$			7500	pF
C_{oss}				920	pF
C_{rss}				220	pF
$t_{d(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = I_T$ $R_G = 1\ \Omega$ (External), Notes 2, 3			45	ns
t_r				45	ns
$t_{d(off)}$				100	ns
t_f				40	ns
$Q_{g(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = I_T$ Notes 2, 3			270	nC
Q_{gs}				60	nC
Q_{gd}				140	nC
R_{thJC}				0.30	K/W
R_{thCK}			0.15		K/W

Source-Drain Diode		Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
Symbol	Test Conditions	min.	typ.	max.
I_S	$V_{GS} = 0\text{ V}$			34 A
I_{SM}	Repetitive; Note 1			136 A
V_{SD}	$I_F = I_T, V_{GS} = 0\text{ V}$, Notes 2, 3			1.5 V
t_{rr}	$I_F = I_T, -di/dt = 100\text{ A}/\mu\text{s}, V_R = 100\text{ V}$		1.4	250 ns
Q_{RM}				μC
I_{RM}				10 A

- Note: 1. Pulse width limited by T_{JM}
 2. Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$
 3. $I_T = 17\text{ A}$

ISOPLUS 247 OUTLINE



- 1 Gate, 2 Drain (Collector)
 3 Source (Emitter)
 4 no connection

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	.190	.205
A ₁	2.29	2.54	.090	.100
A ₂	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b ₁	1.91	2.13	.075	.084
b ₂	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45 BSC		.215 BSC	
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190

See IXFN 34N80 data sheet for characteristic curves.